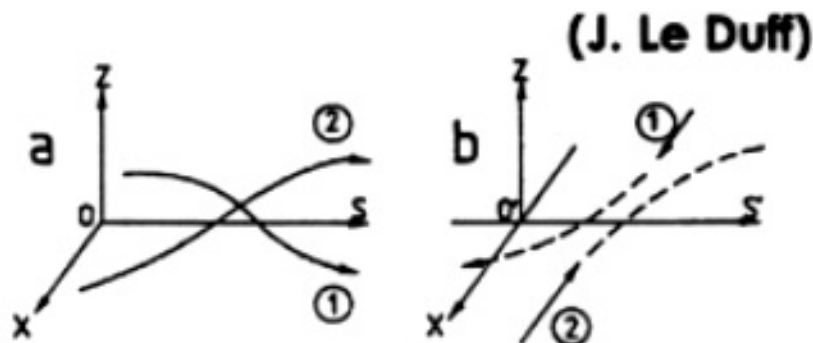


Touschek Effect

(J. Le Duff)

- Single intra-beam Coulomb scattering events in the horizontal plane leading to particle loss mostly due to $\partial E/E$ aperture.



Coulomb scattering of two particles inside the bunch.
(a) Laboratory system, (b) Centre-of-mass system.

- The scattering rate is given by

$$\frac{dN}{dt} = \int_V \frac{\sigma_T}{\gamma^2} v n^2 dV$$

V =bunch volume, σ_T =total cross section

n =density

Touschek Effect (cont'd)

- The particle loss rate then is after substantial manipulation:

$$\frac{1}{N} \frac{dN}{dt} = \frac{1}{\tau} = \frac{Nr_0^2 c}{8\pi\sigma_x\sigma_y\sigma_s} \frac{\lambda^3}{\gamma^2} D(\xi)$$

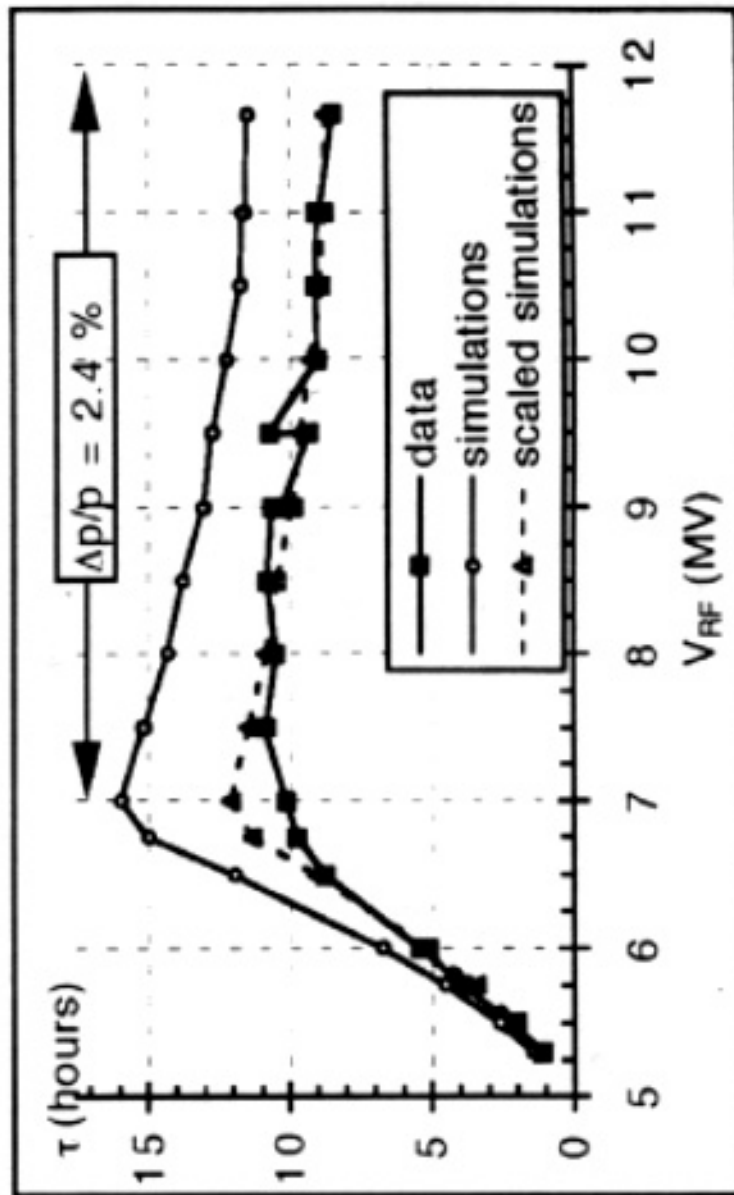
where

$$\xi = \left(\frac{\Delta E / E}{\gamma} \right)^2 \frac{\beta_x}{\epsilon_x}$$

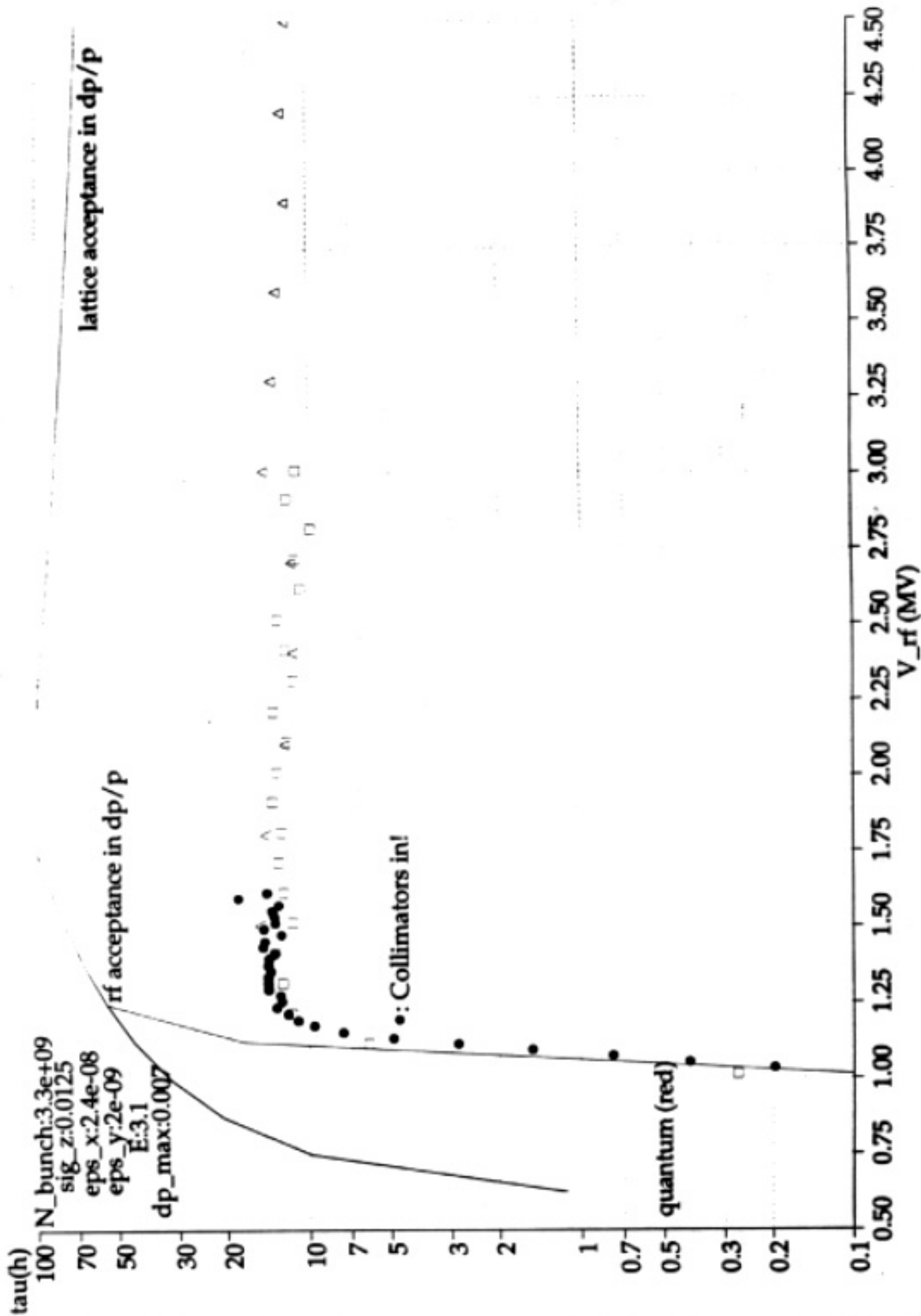
and

$$D(\xi) = \sqrt{\xi} \left(\ln \left(\frac{1}{1.78\epsilon_x} \right) - \frac{3}{2} \right)$$

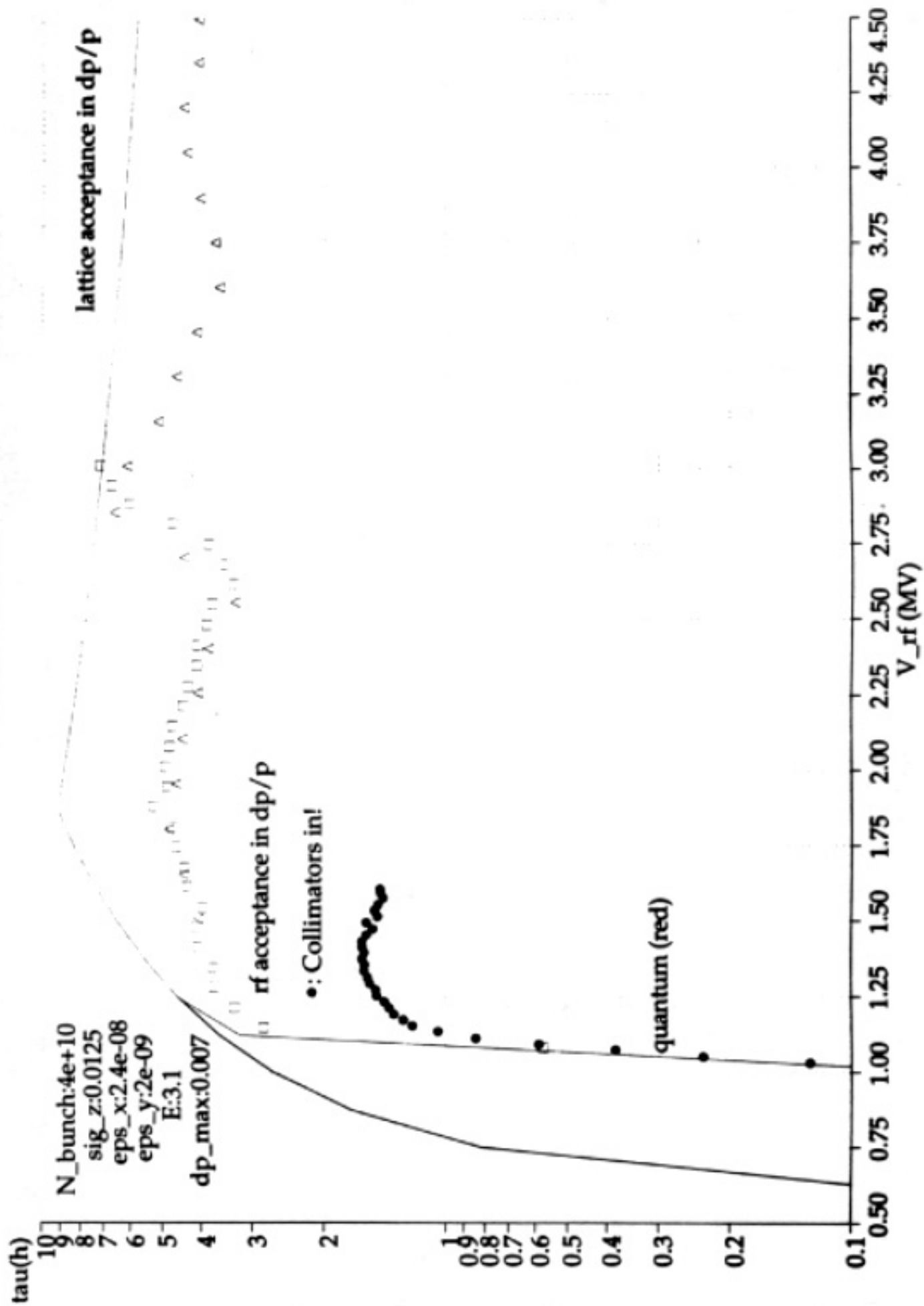
(H. Bruck's approximation for $\xi \leq 0.01$)



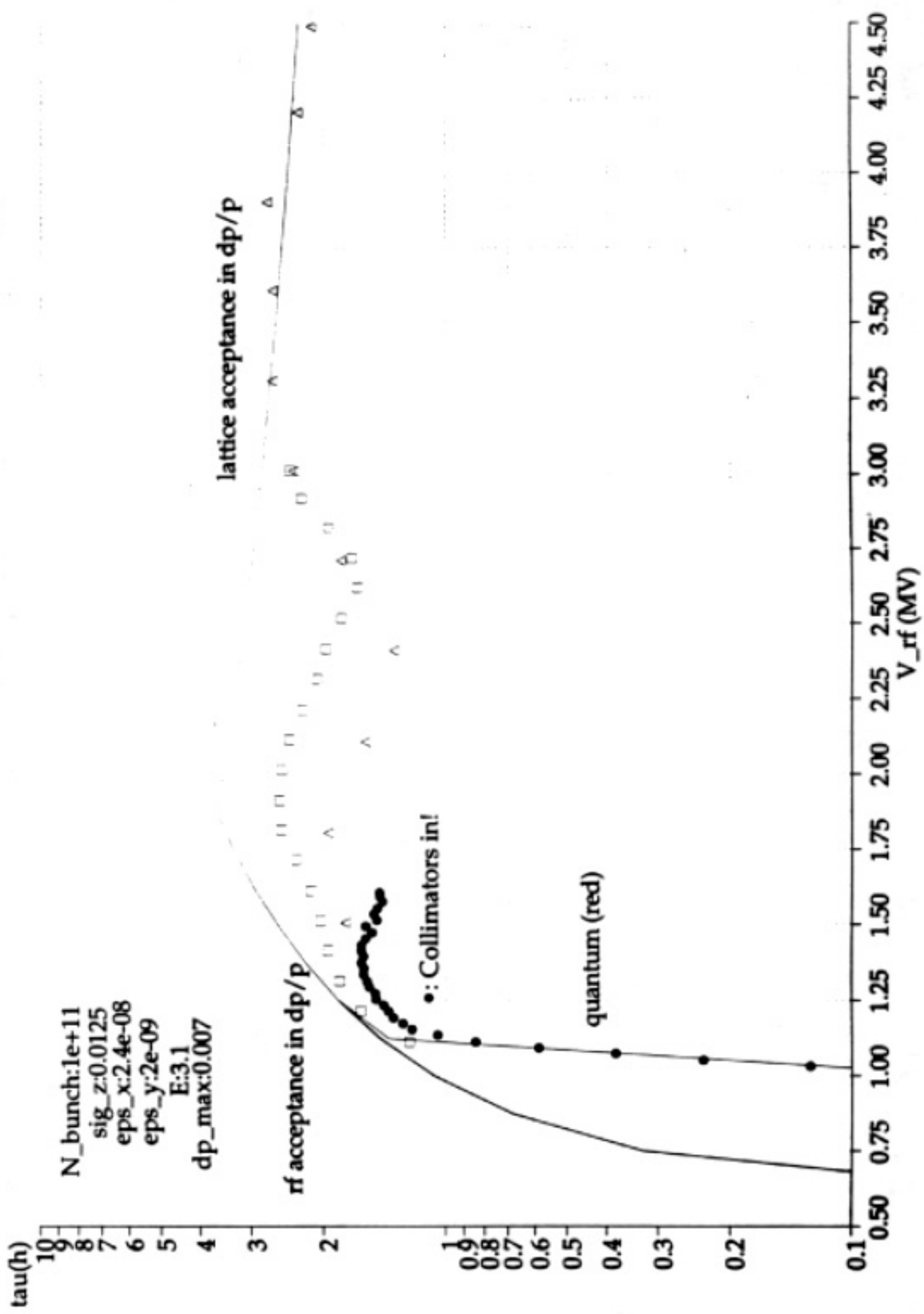
Touschek life time for LER70 μ A bunch, no wiggler



Touschek life time for LER1 mA bunch, no wiggler



Touschek life time for LER 2.5 mA bunch, no wiggler



LER beam lifetime vs bunch current, 35 mA total current

